

30V P-Channel Power MOSFET

DESCRIPTION

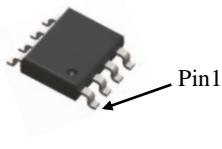
The JRM08P02 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge. It can be used in a wide variety of applications.

Application

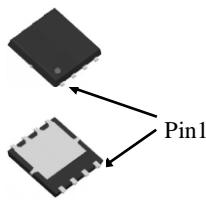
- Power switching application
- Hard switched and High frequency circuits
- Battery Protection

KEY CHARACTERISTICS

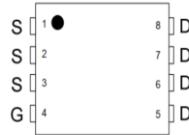
- $V_{DS} = -20V, I_D = -40A$ (PDFN3.3*3.3)
 $I_D = -25A$ (SOP8)
- $R_{DS(ON)} < 10m\Omega$ @ $V_{GS}=-10V$
- $R_{DS(ON)} < 15m\Omega$ @ $V_{GS}=-4.5V$
- High density cell design for lower $R_{DS(on)}$
- Excellent package for good heat dissipation



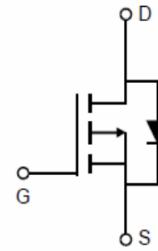
SOP8



PDFN 3.3*3.3



Package Top View



Schematic diagram

Package Marking And Ordering Information

Device Marking	Ordering Codes	Package	Product Code	Packing
M08P02	JRM08P02-R	PDFN3.3*3.3	JRM08P02	Tape Reel
M08P02	JRM08P02-E	SOP8	JRM08P02	Tape Reel

Absolute Maximum Ratings ($T_A=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D (PDFN3.3*3.3)	-40	A
	I_D (SOP8)	-25	A
Drain Current-Pulsed (Note 1)	I_{DM} (PDFN3.3*3.3)	-160	A
	I_{DM} (SOP8)	-100	A
Maximum Power Dissipation($T_c=25^\circ C$)	P_D (PDFN3.3*3.3)	16	W
	P_D (SOP8)	7.5	W
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	°C

Thermal Characteristic

Thermal Resistance,Junction-to-Ambient	$R_{\theta JC}$ (PDFN3.3*3.3)	7.8	°C/W
	$R_{\theta JC}$ (SOP8)	16.7	°C/W

Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =-250μA	-20	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-20V, V _{GS} =0V	-	-	-1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
On Characteristics						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =-250μA	-0.4	-0.7	-1.0	V
Drain-Source On-State Resistance ^(Note 2)	R _{D(S)ON}	V _{GS} =-10V, I _D =-20A	-	6	8	mΩ
		V _{GS} =-4.5V, I _D =-13A	-	7	9	mΩ
Forward Transconductance	g _F	V _{DS} =-5V, I _D =-14A	-	73	-	S
Dynamic Characteristics						
Input Capacitance	C _{iss}	V _{DS} =-10V, V _{GS} =0V, f=1.0MHz	-	3500	-	pF
Output Capacitance	C _{oss}		-	520	-	pF
Reverse Transfer Capacitance	C _{rss}		-	430	-	pF
Switching Characteristics (Note 3)						
Turn-on Delay Time	t _{d(on)}	V _{DD} =-10V, ID=-13A, V _{GS} =-10V, R _{GEN} =3Ω	-	19	-	nS
Turn-on Rise Time	t _r		-	31	-	nS
Turn-Off Delay Time	t _{d(off)}		-	135	-	nS
Turn-Off Fall Time	t _f		-	60	-	nS
Total Gate Charge	Q _g	V _{DS} =-10V, ID=-15A V _{GS} =-4.5V	-	45	-	nC
Gate-Source Charge	Q _{gs}		-	10	-	nC
Gate-Drain Charge	Q _{gd}		-	10	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage	V _{SD}	V _{GS} =0V, I _s =-1 A	-	-	-1.2	V

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
3. Guaranteed by design, not subject to production.

Characteristics Curves

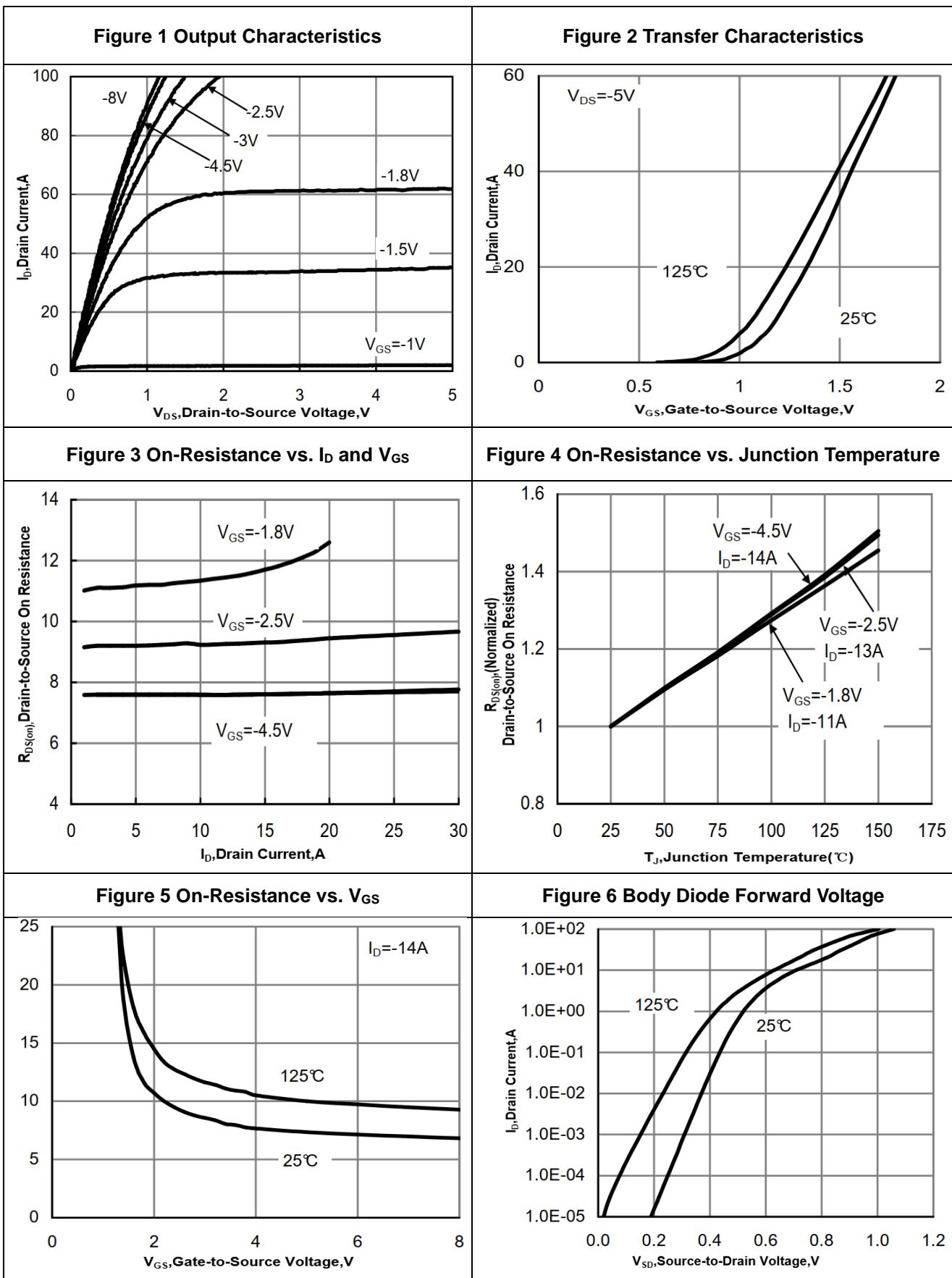


Figure 7 Gate-Charge Characteristics

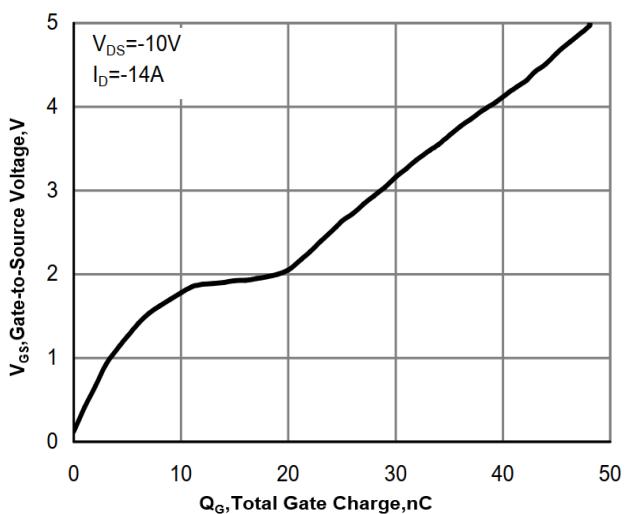


Figure 8 Capacitance Characteristics

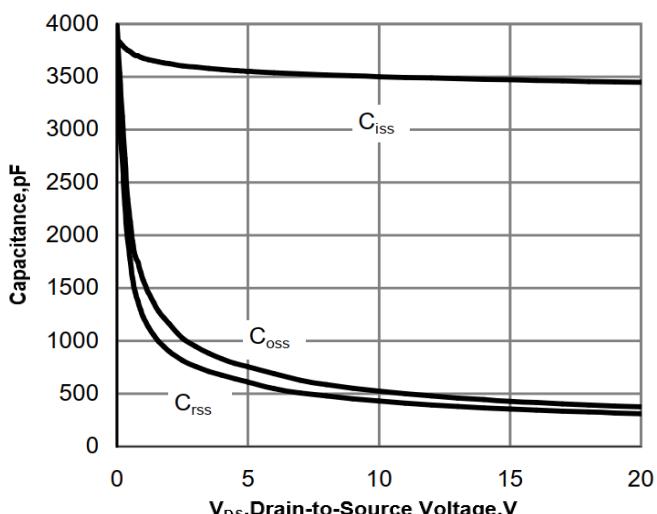


Figure 9a Maximum Forward Biased Safe Operation Area (PDFN3.3*3.3)

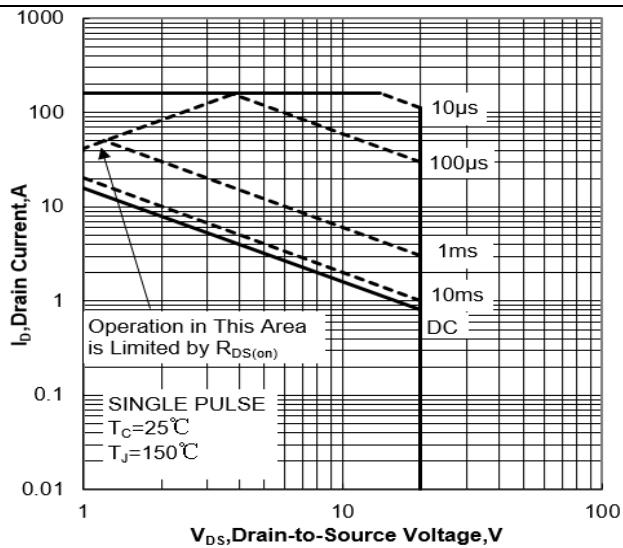


Figure 9b Maximum Forward Biased Safe Operation Area (SOP8)

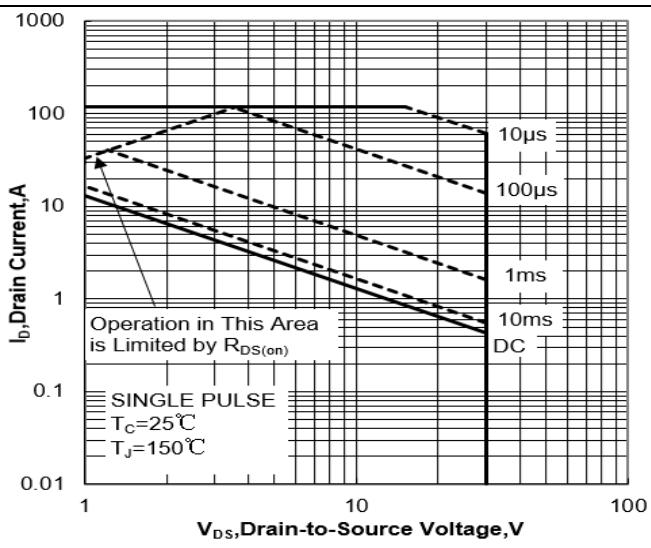


Figure 10a Single Pulse Power Rating Junction-to-Ambient (PDFN3.3*3.3)

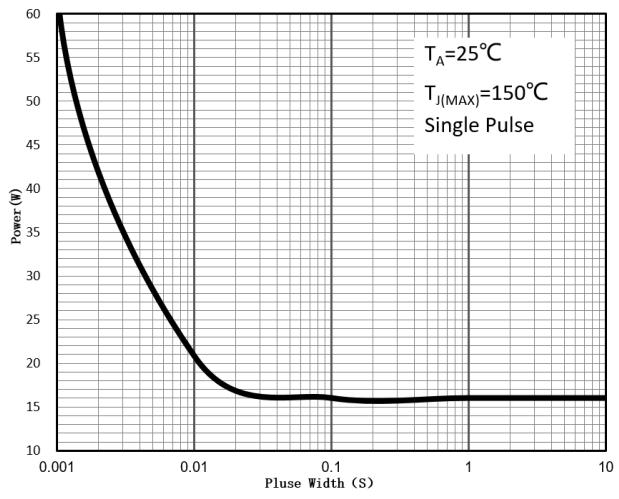


Figure 10b Single Pulse Power Rating Junction-to-Ambient (SOP8)

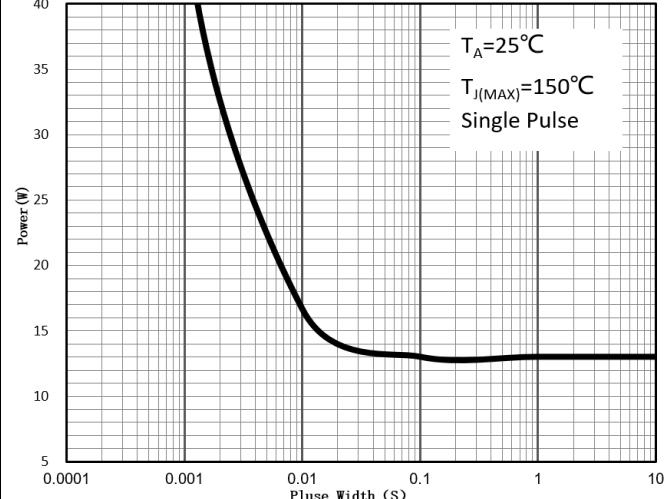


Figure 11a Normalized Maximum Transient Thermal Impedance (PDFN3.3*3.3)

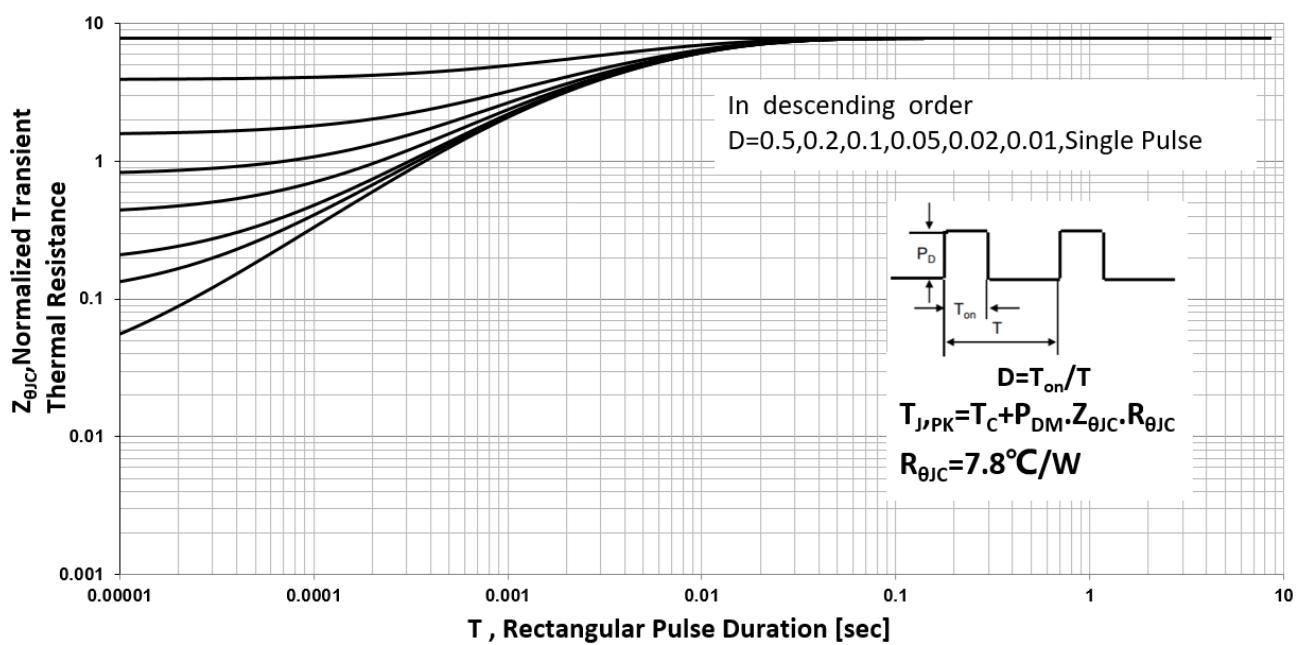
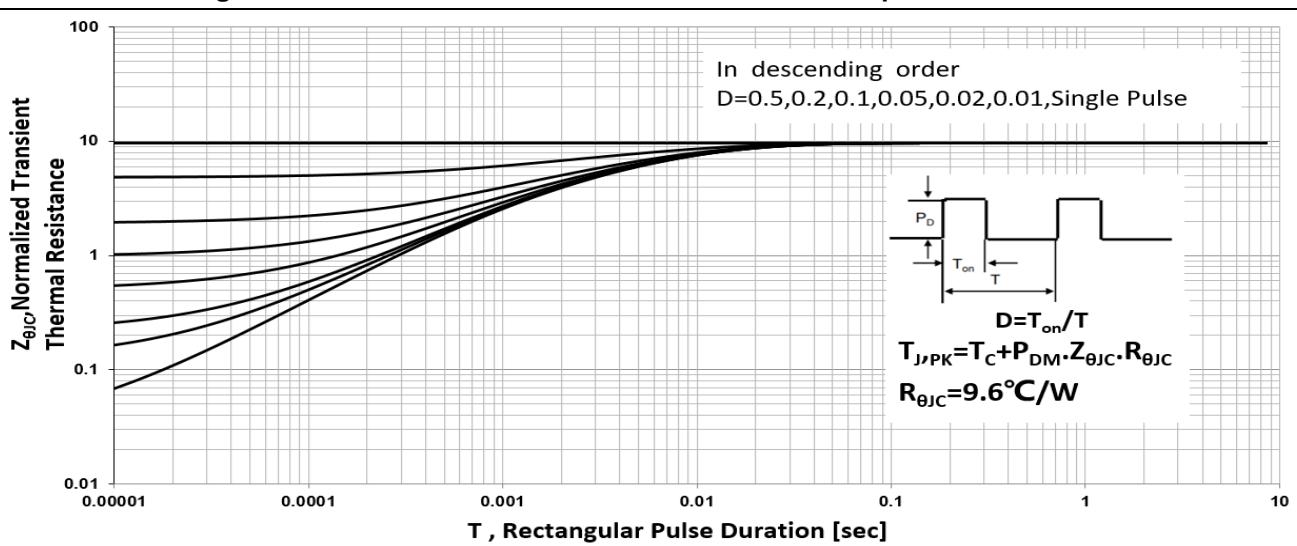
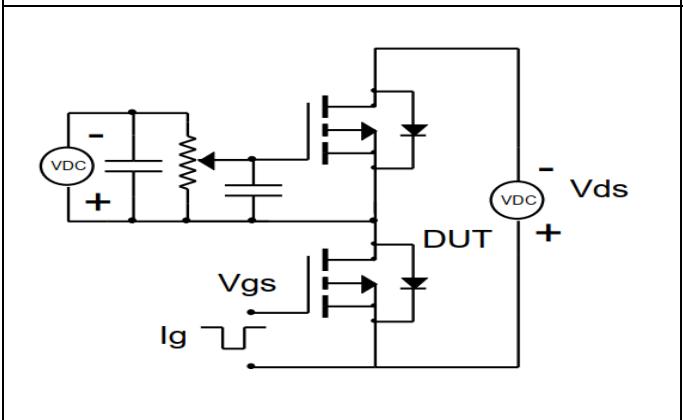
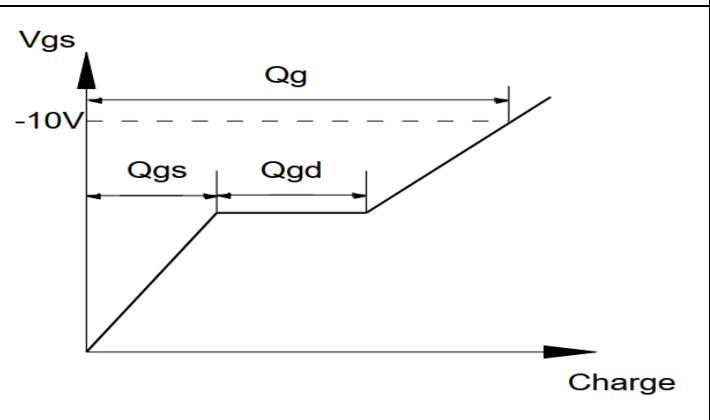
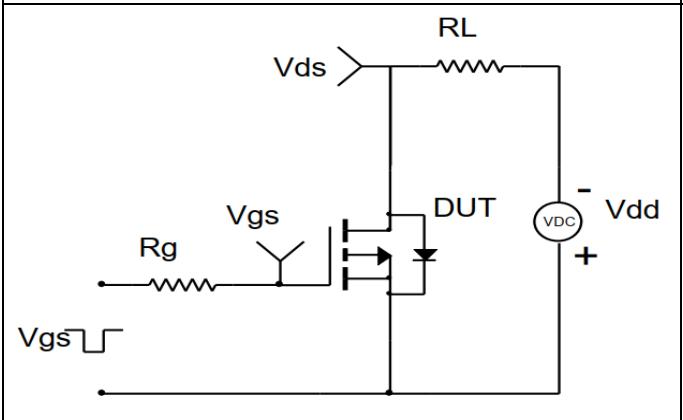
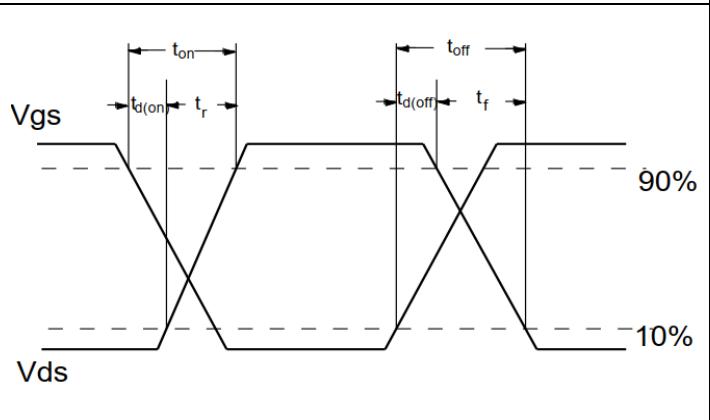
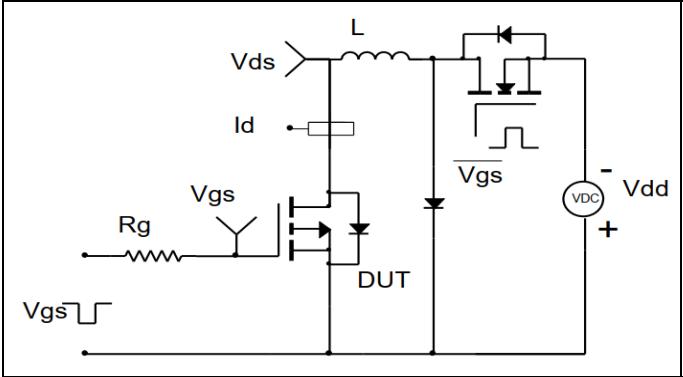
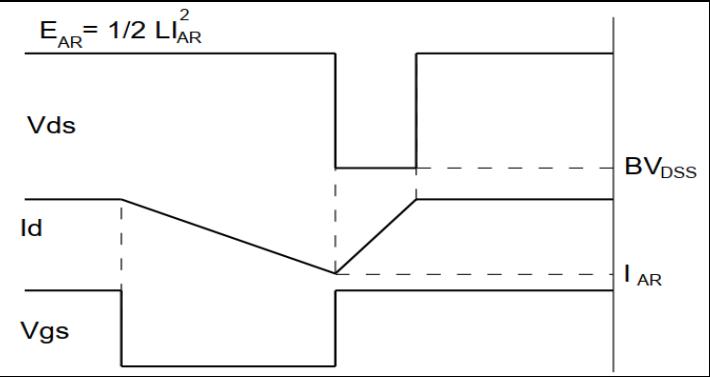
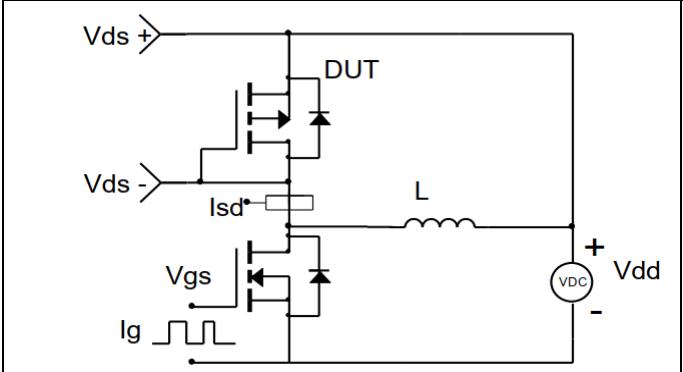
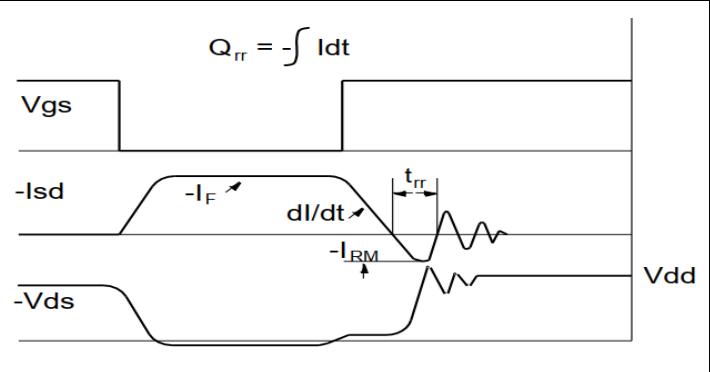


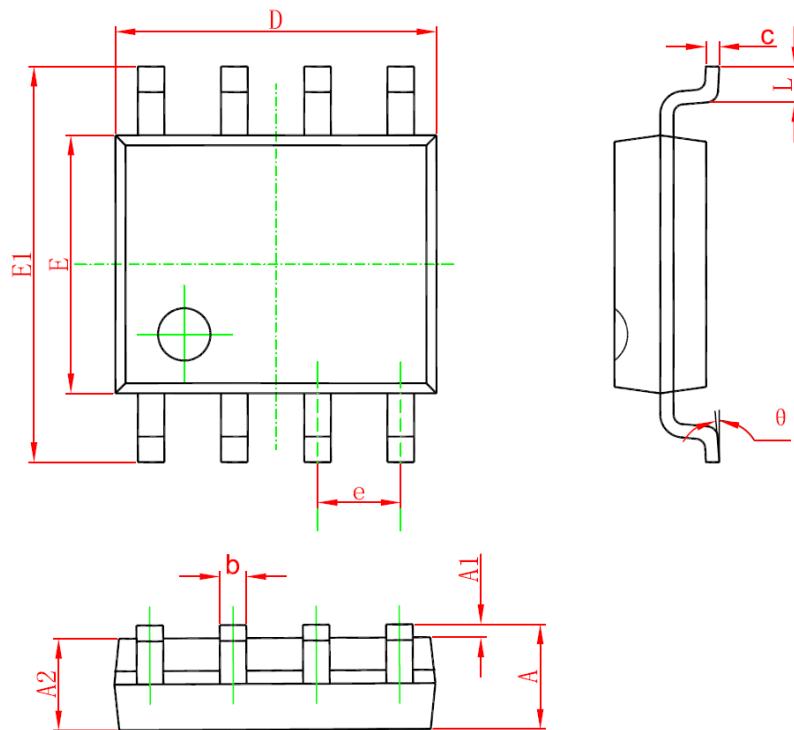
Figure 11b Normalized Maximum Transient Thermal Impedance (SOP8)



Test Circuit and Waveform

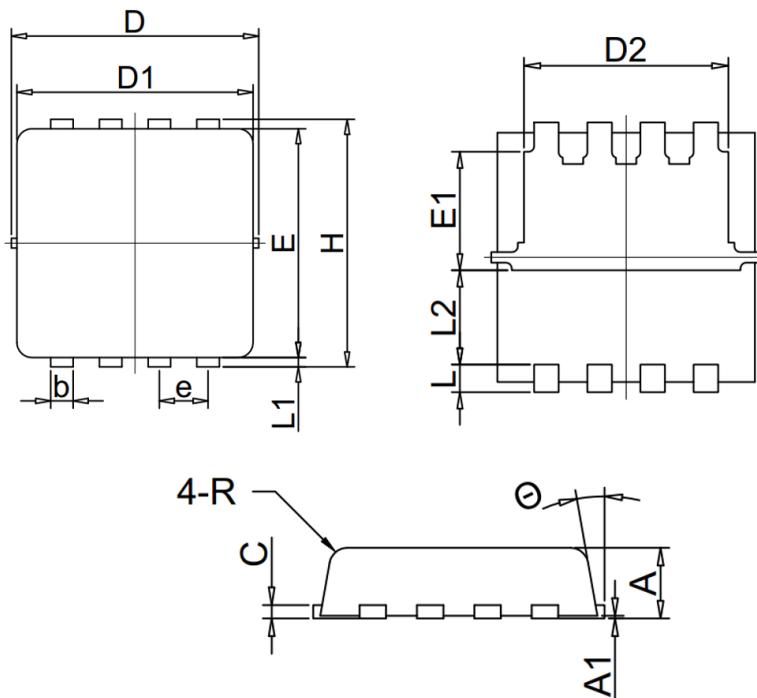
Gate Charge Test Circuit	Gate Charge Test Waveform
	
Resistive Switching Test Circuit	Resistive Switching Test Waveforms
	
Unclamped Inductive Switching (UIS) Test Circuit	Unclamped Inductive Switching (UIS) Test Waveforms
	
Diode Recovery Test Circuit	Diode Recovery Test Waveforms
	

Package Description



Symbol	Dimensions Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270 (BSC)		0.050 (BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°

SOP8 Package



SYMBOL	MIN	NOM	MAX
A	0.70	0.80	0.90
A1	0.00	0.03	0.05
b	0.24	0.30	0.35
c	0.152REF		
D	3.25	3.32	3.40
D1	3.05	3.15	3.25
D2	2.40	2.50	2.60
E	3.00	3.10	3.20
E1	1.35	1.45	1.55
e	0.65BSC		
H	3.20	3.30	3.40
L	0.30	0.40	0.15
L1	0.10	0.15	0.20
L2	1.13REF		
R	0.20REF		
Θ	6°	10°	14°

PDFN3.3*3.3 Package

NOTE:

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shanghai Jerrett reserves the right to make changes in this specification sheet and is subject to change without prior notice.